

--40. (New) The scanning exposure apparatus according to claim 36, wherein the first measurement system emits the biaxial beams along the scanning axis.--

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--41. (New) The scanning exposure apparatus according to claim 37, wherein the second measurement system emits the biaxial beams along the scanning axis.--

--42. (New) The scanning exposure apparatus according to claim 38, wherein the second measurement system emits the biaxial beams along the scanning axis.--

REMARKS

Claims 1-10, 12-28 and 30-42 are pending. By this Amendment, claims 32-42 are added.

No new matter is added by the above amendments. With respect to the biaxial beams recited, for example, in new claims 32-34 and 36-38, see the original specification at, for example, page 63, lines 14-17.

The Examiner is requested to consider U.S. Patent No. 5,715,064, which is enclosed with the attached Information Disclosure Statement.

Further examination and allowance in due course are earnestly solicited.

Respectfully submitted,



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MAC/ccs

Attachments:

Request for Continued Examination
Information Disclosure Statement
Amendment Transmittal

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<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>
